Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/782,306	WENZEL ET AL.
Examiner	Art Unit
Devesh Khare	1623

SEARCHED				
Class	Subclass	Date	Examiner	
514	567,26			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STIC Seed	7/14/05	ay		
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